

• General Description

It combines trench MOSFET technology with a low resistance package to provide extremely low $R_{DS(ON)}$.

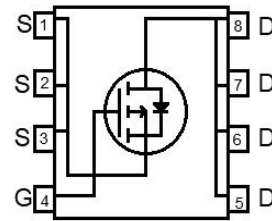
• Features

- AEC-Q101 Qualified
- Low $R_{DS(ON)}$ to minimize conductive loss
- High GOX reliability
- Low Thermal resistance

• Application

- BLDC Motor driver
- DC-DC
- Battery protection

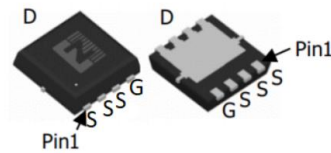
• Product Summary



$V_{DS} = -40V$

$R_{DS(ON)} = 26m\Omega$

$I_D = -20A$



DFN3*3



• Ordering Information:

| | |
|---------------------------|------------|
| Part NO. | ZMA260P04M |
| Marking | 260P04 |
| Packing Information | REEL TAPE |
| Basic ordering unit (pcs) | 5000 |

• Absolute Maximum Ratings ($T_C=25^\circ C$)

| Parameter | Symbol | Conditions | Value | Unit |
|--------------------------------|-----------|---|-------------|------------|
| Drain-Source Voltage | V_{DS} | | -40 | V |
| Gate-Source Voltage | V_{GS} | | ± 20 | V |
| Continuous Drain Current | I_D | $T_C=25^\circ C$ | 20 | A |
| | I_D | $T_C=75^\circ C$ | 18 | A |
| | I_D | $T_C=100^\circ C$ | 15 | A |
| Pulsed Drain Current | I_{DM} | pulsed; $t_p \leq 10 \mu s$; $T_{mb} = 25^\circ C$; | 71 | A |
| Total Power Dissipation | P_D | $T_C=25^\circ C$ | 33 | W |
| Total Power Dissipation | P_D | $T_A=25^\circ C$ | 2.5 | W |
| Operating Junction Temperature | T_J | | -55 to +175 | $^\circ C$ |
| Storage Temperature | T_{STG} | | -55 to +175 | $^\circ C$ |
| Single Pulse Avalanche Energy | E_{AS} | $L=0.1mH, V_{GS}=-10V, R_g=25\Omega,$ | 24 | mJ |
| | | $L=0.5mH, V_{GS}=-10V, R_g=25\Omega,$ | 50.4 | mJ |
| ESD Level (HBM) | CLASS 1C | | | |

•Thermal resistance

| Parameter | Symbol | Min. | Typ. | Max. | Unit |
|---|------------|------|------|------|---------------|
| Thermal resistance, junction - case | R_{thJC} | | - | 4.5 | $^{\circ}C/W$ |
| Thermal resistance, junction-ambient ^② | R_{thJA} | | - | 60 | $^{\circ}C/W$ |
| Soldering temperature | T_{sold} | | - | 260 | $^{\circ}C$ |

•Electronic Characteristics

| Parameter | Symbol | Condition | Min. | Typ. | Max. | Unit |
|-----------------------------------|--------------|----------------------------------|------|------|------|------------|
| Drain-Source Breakdown Voltage | BV_{DSS} | $V_{GS}=0V, I_D = -250\mu A$ | 40 | | | V |
| Gate Threshold Voltage | $V_{GS(TH)}$ | $V_{GS}=V_{DS}, I_D = -250\mu A$ | -1.3 | -1.7 | -2.5 | V |
| Drain-Source Leakage Current | I_{DSS} | $V_{GS}=0V, V_{DS}= -40V$ | | | 1 | μA |
| Gate- Source Leakage Current | I_{GSS} | $V_{GS}=\pm 20V, V_{DS}=0V$ | | | 100 | nA |
| Static Drain-source On Resistance | $R_{DS(ON)}$ | $V_{GS}=-10V, I_D = -10A$ | | 26 | 34 | m Ω |
| Diode Forward Voltage | V_{FSD} | $V_{GS}=0V, I_{SD} = -10A$ | | | 1.3 | V |

•Dynamic characteristics

| Parameter | Symbol | Condition | Min. | Typ. | Max. | Unit |
|------------------------------|--------------|--|------|------|------|----------|
| Input capacitance | C_{iss} | $f = 1MHz, V_{DS}=-25V$ | - | 1370 | | pF |
| Output capacitance | C_{oss} | | - | 101 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 67 | - | |
| Gate Resistance | R_g | $f = 1MHz$ | - | 7.5 | | Ω |
| Total gate charge | Q_g | $V_{DD} = -15V, I_D = -20A$ $V_{GS} = -10V$ | - | 20.8 | - | nC |
| Gate - Source charge | Q_{gs} | | - | 3.5 | - | |
| Gate - Drain charge | Q_{gd} | | - | 3.6 | - | |
| Turn-ON Delay time | $t_{D(on)}$ | $V_{GS}=-10V, V_{DS}=-15V,$ $R_G = 3.3\Omega, I_D = -20A$ | - | 21 | - | ns |
| Turn-ON Rise time | t_r | | - | 53 | - | ns |
| Turn-Off Delay time | $t_{D(off)}$ | | - | 46 | - | ns |
| Turn-Off Fall time | t_f | | - | 42 | - | ns |
| Reverse Recovery Time | t_{RR} | $V_{DD}=-20V, dI_S/dt =$ $100A/\mu s, I_S = -50A$ | - | 35 | - | ns |
| Reverse Recovery Charge | Q_{RR} | | - | 42 | - | nC |

Fig.1 Gate-Charge Characteristics

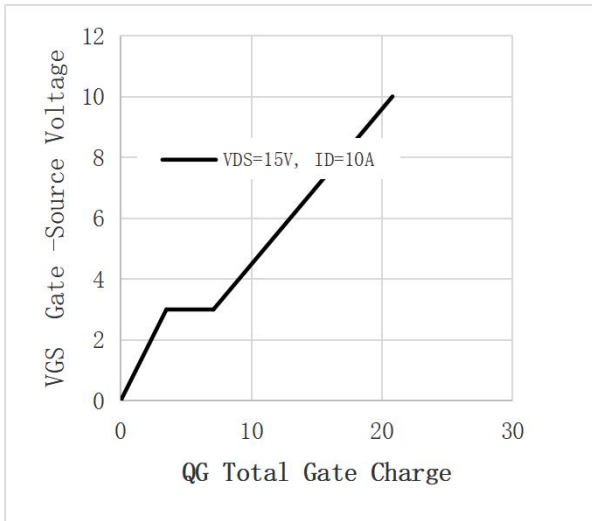


Fig.2 Capacitance Characteristics

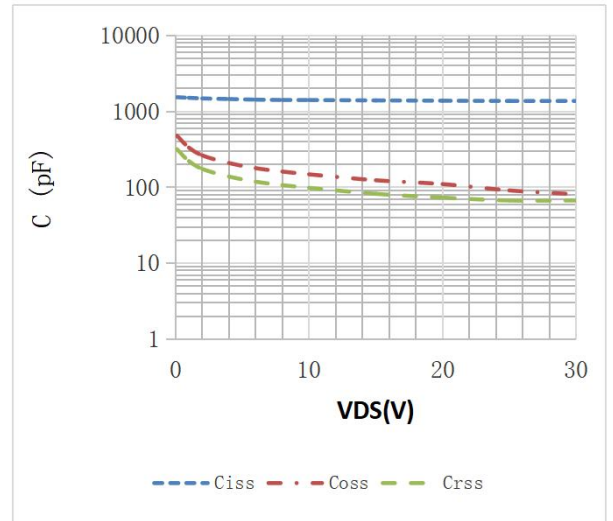


Fig.3 Power Dissipation

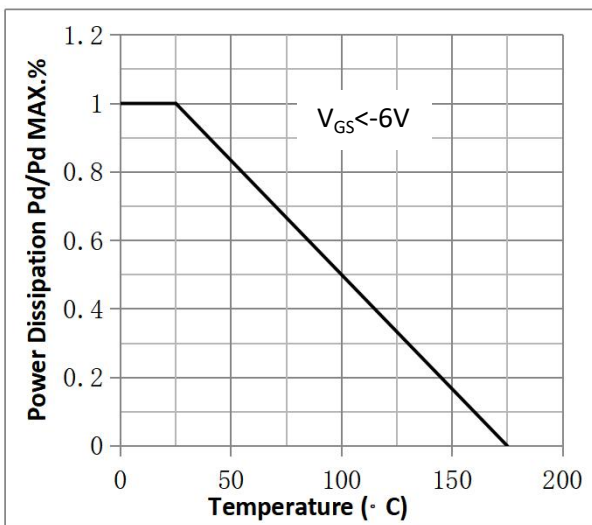


Fig.4 Typical output Characteristics

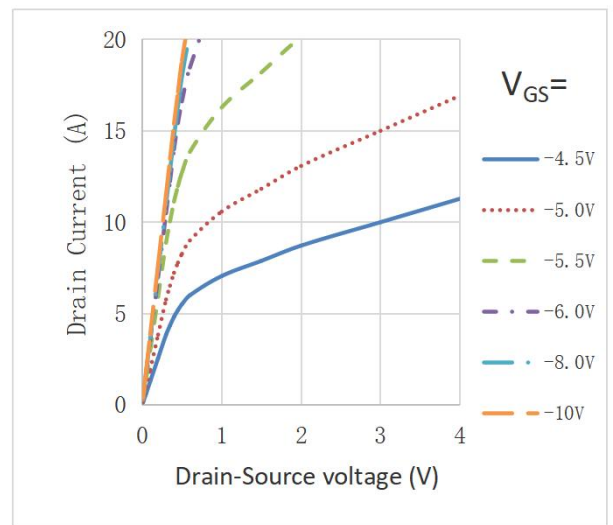


Fig.5 Threshold Voltage V.S Junction Temperature

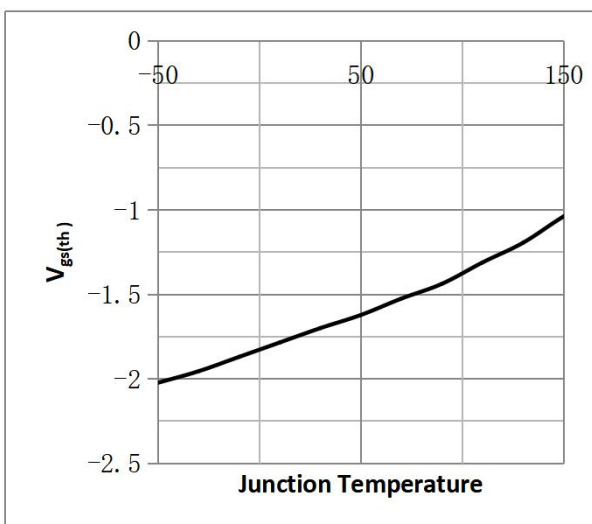


Fig.6 Resistance V.S Drain Current

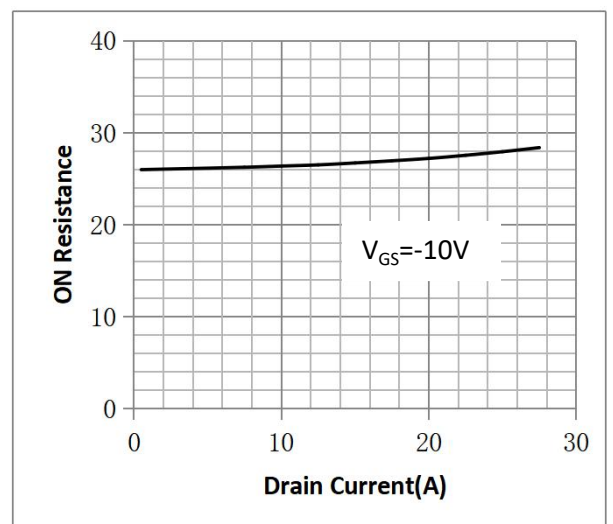


Fig.7 On-Resistance VS Gate Source Voltage

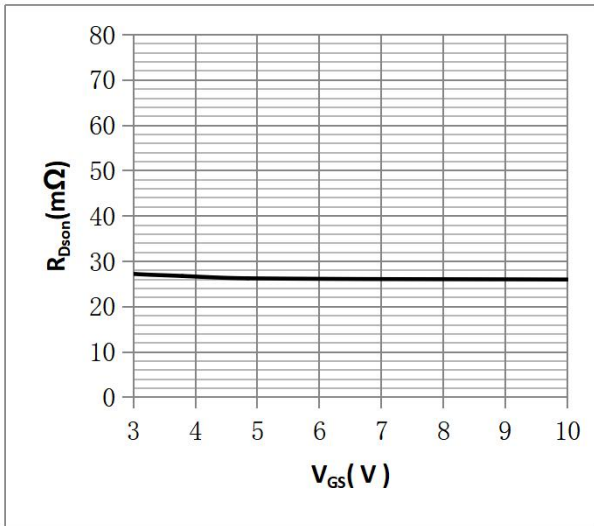


Fig.8 On-Resistance V.S Junction Temperature

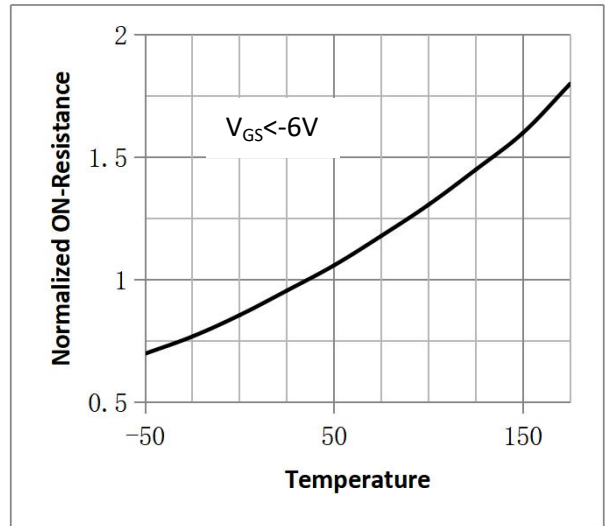


Figure 9. Diode Forward Voltage vs. Current

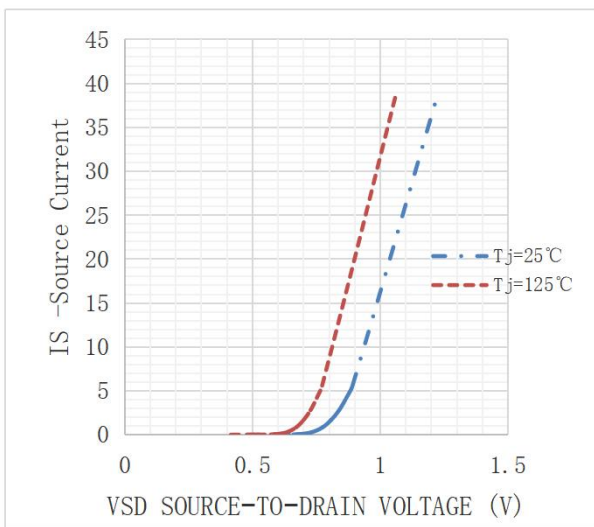


Figure 10. Transfer Characteristics

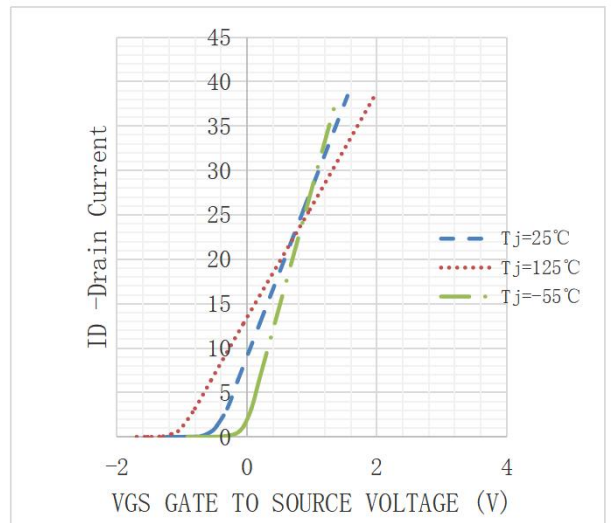


Fig.11 Safe Operating Area

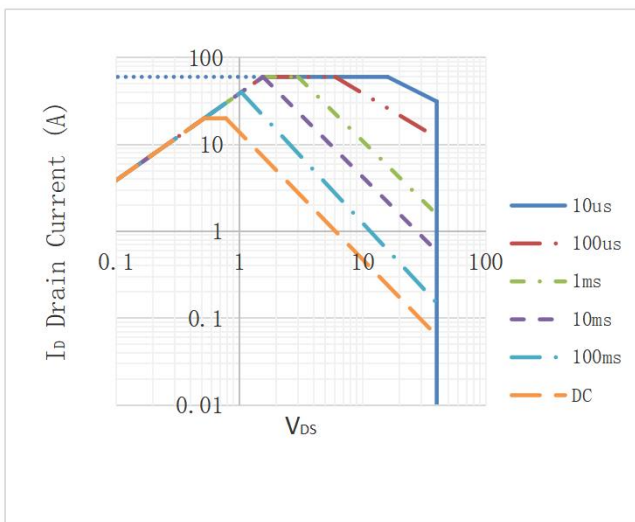
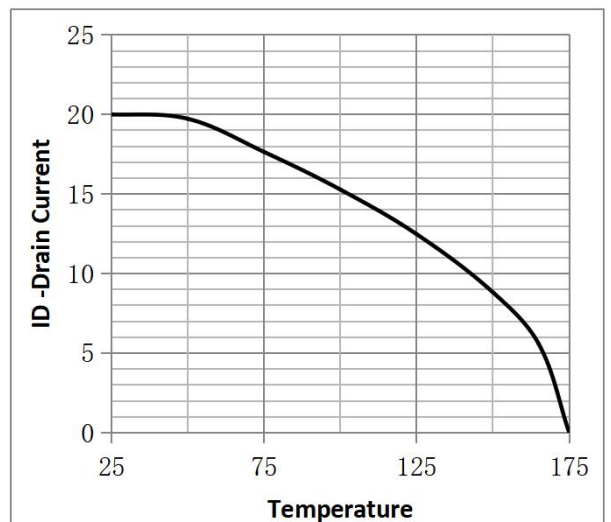
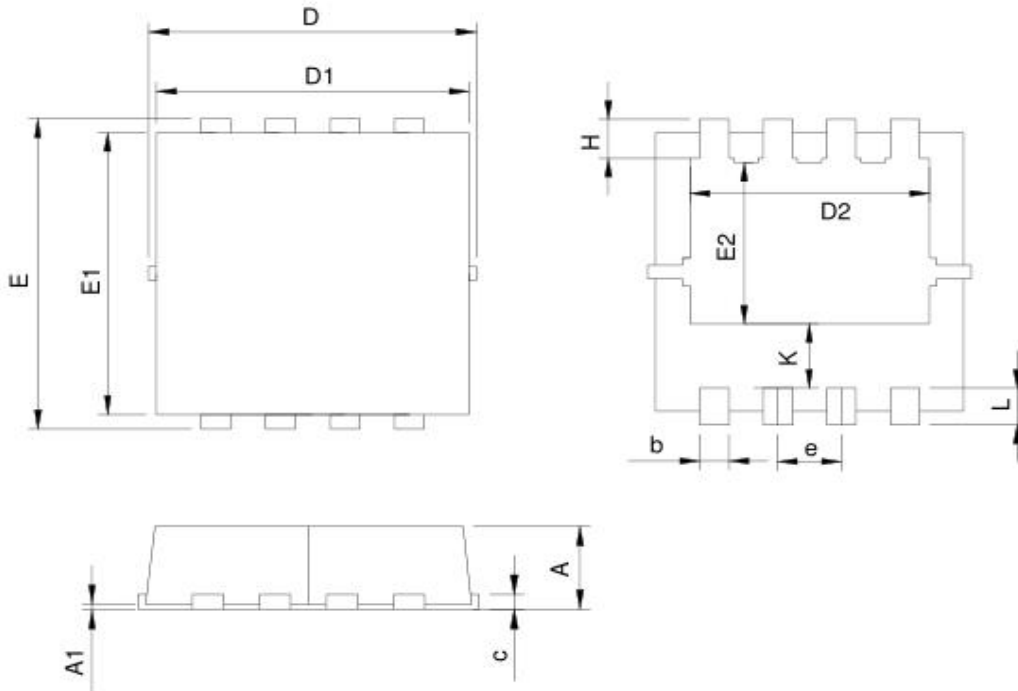


Fig.12 ID vs. Junction Temperature

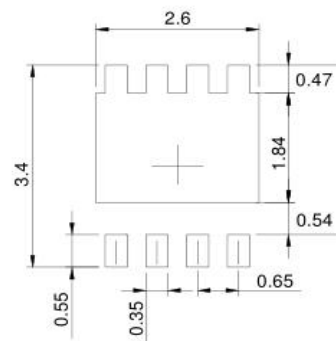


•DFN3*3 Package Outline



| SYMBOL | DFN3.3x3.3-8 | | | |
|--------|--------------|------|-----------|-------|
| | MILLIMETERS | | INCHES | |
| | MIN. | MAX. | MIN. | MAX. |
| A | 0.70 | 1.00 | 0.028 | 0.039 |
| A1 | 0.00 | 0.05 | 0.000 | 0.002 |
| b | 0.25 | 0.35 | 0.010 | 0.014 |
| c | 0.14 | 0.20 | 0.006 | 0.008 |
| D | 3.10 | 3.50 | 0.122 | 0.138 |
| D1 | 3.05 | 3.25 | 0.120 | 0.128 |
| D2 | 2.35 | 2.55 | 0.093 | 0.100 |
| E | 3.10 | 3.50 | 0.122 | 0.138 |
| E1 | 2.90 | 3.10 | 0.114 | 0.122 |
| E2 | 1.64 | 1.84 | 0.065 | 0.072 |
| e | 0.65 BSC | | 0.026 BSC | |
| H | 0.32 | 0.52 | 0.013 | 0.020 |
| K | 0.59 | 0.79 | 0.023 | 0.031 |
| L | 0.25 | 0.55 | 0.010 | 0.022 |

RECOMMENDED LAND PATTERN



UNIT: mm

Note:

- ① Pulse Test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$, Accumulation time ≤ 50 hours; For DC , the following test conditions can be passed: $V_{GS}=-20V/+5V$, $T_j=175^\circ\text{C}$, $t=1000$ hours;
- ② Device mounted on FR-4 substrate PC board, 2oz copper, with thermal bias to bottom layer 1inch square copper plate:

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Revision History

| Version | Date | Change |
|---------|-----------|---|
| A | 2021.2.3 | NEW |
| B | 2021.11.7 | 1.Modified Typical output Characteristics curve |
| C | 2022.5.6 | 1.Add Reach,HF figure 2.Modified ID curve |
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